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SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 249761US2S DIV		SERIAL NO. New Divisional Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideo ANDO, et al.			
				FILING DATE Herewith		GROUP Unassigned 26/6	
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
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<i>DN</i>	AB	5,991,502	11/1999	KAWAKAMI et al.	—	—	
<i>DN</i>	AC	6,181,870	01/2001	OKADA et al.	—	—	
<i>DN</i>	AD	6,253,026	06/2001	SAEKI et al.	—	—	
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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>DN</i>	AH	JP 11-16824	01/22/99	JAPAN			X
<i>DN</i>	AI	JP 2000-13728	01/14/00	JAPAN			X
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<i>DN</i>	AAE	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-282024 (with English translation)					
<i>DN</i>	AAF	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-260103 (with English translation)					
<i>DN</i>	AAG	Japanese Office Action (Notification of Reasons for Rejection) re: Patent Application JP 9-398346, mailing date: July 30, 2002, mailing no. 250720 (with English translation)					
Examiner <i>Huy Nguyen</i>					Date Considered <i>9/12/05</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
249761US2SDIVSERIAL NO.
10/801,835

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Hideo ANDO, et al.FILING DATE
March 17, 2004GROUP
2645 2616

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

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☐ Additional References sheet(s) attached

Examiner

Date Considered

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